



JAPANESE
INDUSTRIAL
STANDARD

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JIS C 0922 : 2002

(IEC 61032 : 1997)

**Protection of persons
and equipment by enclosures
for electrical apparatus—
Probes for verification**

ICS 13.180; 13.260; 29.020

Reference number : JIS C 0922 : 2002 (E)

Foreword

This translation has been made based on the original Japanese Industrial Standard established by the Minister of Economy, Trade and Industry through deliberations at the Japanese Industrial Standards Committee in accordance with the Industrial Standardization Law:

This Standard has been made based on **IEC 61032 : 1997** *Protection of persons and equipment by enclosures—Probes for verification* for the purposes of making easy to compare this Standard with International Standards; to prepare Japanese Industrial Standard conforming with International Standards; and to propose a draft of International Standard which is based on Japanese Industrial Standard.

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In the event of any doubts arising as to the contents,
the original JIS is to be the final authority.

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Protection of persons and equipment by enclosures for electrical apparatus— Probes for verification

Introduction This Japanese Industrial Standard has been prepared based on **IEC 61032** *Protection of persons and equipment by enclosures—Probes for verification* published in 1997 as the second edition without any modification in technical contents.

The “Information” underlined with dots means the matters not stated in the International Standard.

1 General

1.1 Scope and object This Standard specifies details and dimensions of test probes intended to verify the protection provided by enclosures of electrical apparatus with regard to:

- protection of persons against access to hazardous parts inside the enclosure;
- protection of the equipment inside the enclosure against ingress of solid foreign objects.

The object of this Standard is:

- to bring together in one publication object probes and access probes currently specified in other standards, together with any necessary new probes;
- to guide technical committees in the selection of test probes;
- to encourage those concerned to specify test probes in accordance with those already specified in this Standard rather than modify details and dimensions;
- to limit the further proliferation of types of test probe.

Note : The International Standard corresponding to this Standard is as follows.

In addition, symbols which denote the degree of correspondence in the contents between the relevant International Standard and **JIS** are IDT (identical), MOD (modified), and NEQ (not equivalent) according to **ISO/IEC Guide 21**.

IEC 61032 : 1997 *Protection of persons and equipment by enclosures—Probes for verification* (IDT)

1.2 General recommendations When selecting probes, priority should be given to IP code probes.

The use of other probes, particularly probes which are not specified in this Standard, should be limited to cases where the use of an IP code probe is for some reason impractical.

Note : The selection of a test probe for a particular purpose is the responsibility of the relevant technical committees.